



Linear Collider Beam Test Workshop 2009

SiLC test beam activities

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On behalf of the SiLC R&D collaboration







- I. Standalone multi-purpose tests system
- II. Combined test beams
- III.Preparation of the combined test beam with calorimetry
- IV.Next years prospects





Standalone multipurpose test beams system



<u>Goals:</u>

- Tests of new sensors technology
- Tests of new Front-End Electronics (FEE)
- Include a reference FEE system (VA1 based)
- Adaptable to various combined tests
- DAQ read both FEE systems (new SiTr130-128 chips & VA1)
- Locate up to five silicon modules







New sensor developments under studies



Conducted by LPNHE:

 Research baseline: wafer 6"-8", 200μm of thickness, pitch of 50 μm, transparency ~70%, active edge



•Classical design named HPK:

- 50µm pitch, 320µm of thickness
- Hammamatsu manufacturing

Surface treatment of silicon wafers: $\rightarrow \sim 20\%$ transmittance \rightarrow Alignment System (IFCA) using an infra-red laser in labs & tests beam \rightarrow Santander – I.Villa, M.Fernandez





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Standalone Test Beam System





- Tests of the friendly aligned HPK sensors with a laser beam embedded
- Tests of other sensors types (new strip technology, new pixel devices)
- Tests of new Front-End Electronics (FEE)
 → SiTr130-128
- Combined tests with other sub-detector prototypes => new such infrastructure are developed and adapted to those tests







Standalone Test Beam System LPNHE - DAQ - Hardware



- Increase of the number of channel to read:
 - Alignment tests=> 2560 voies
 - EUDET and transnational tests (mi-2010) => 15000 à 20000 voies
 - 2011-2012 -> much more !!!
- Evolutive DAQ Hardware ToolKit (EUDET deliverable)
 - Adapted to both: VA1 (référence) prototypes SiTr-130 and next, mix mode (VA1+SiTr chips)
 - Altera/Usb \rightarrow Altera/Ethernet under way
 - FPGA/(USBx, Light Peak)? for the future







Standalone Test Beam System LPNHE - DAQ - Software



Acquisition needs:

- Increasing of the Data size management
- Addressing of the data
- On-line control
- Flexibility

Narval is the main frame (ADAoriented)

- → module programming: ADA/C/C++
- \rightarrow Can be interfaced with any other DAQ
- \rightarrow FPGA system is handled by a full VHDL software package.



Master: Narval





Standalone Test Beam System

LPNHE - test beam & alignment



Next Tests Beam preparation



tests beam @ CERN & laser tests @ Santander

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Combined test beams with EUDET telescope since 2007





SiLC combined test beam in 2009

Testbeam at CERNs SPS (19. to 26. August 2009)

- CERN SPS North Area: H6B
- Low intensity 120 GeV with (Pi+:55.67%, p+:38.95%, K+:5.38%)

Configuration:

- EUDET Beam Telescope to get triggers & tracks
- Readout chain from HEPHY's Electronic 2 Group
- Slow control/monitoring: HV, T, RH, Cooling
- Full remote control

<u>Results:</u>

- 3.2 Million events
- 1 TB of data

Full Logbook at http://elog.hephy.at/testbeam-SPS09/

Source: Thomas Bergauer Institute of High Energy Physics





2009/11/03



ITE Sensors & others



HEPHY Vienna and Institute of Electron Technology (ITE) Warsaw Sensor

- 2 x Sandard
- 2 x Pitch Adapter Single layer
- 2 x Pitch Adapter Double layer
- 3 x 512 channels
- 2 x Alignment Modules
- 2 x SiLC-HPK half-moons for test structure measurements
- Stack of last years multi-geometry sensors for calibration





512 channels



PAS



Institute of High Energy Physics

PAD





Results

signal loss and cross talk



•Each hit position represents SNR of a cluster with hit location estimated at the respective strip

•Closer look on signals and noise separately necessary to disentangle effects



Correlations using rank correlation coefficient (Kendall's Tau)





2009/11/03



SiLC combined testbeam

Alignment module runs



- Alignment modules:
 - Two modules mounted on base plate together with laser collimator (end of optical fibre)
 - Beam and Laser runs





LCTW' · 9 - LAL - Framerko Dragioeviandre Charpy@lpnhe.inYp".fr



LPTPC-SiLC combined test beams : silicon envelope (2009@DESY)

- <u>Goal</u>: study the resolution improvements of the Large Prototype TPC by adding a precise measured point of the track (order of 10µm), inside the gap, between magnet and TPC, on both sides of the TPC.
- This set-up allow the test of a first prototype of the silicon envelope with the TPC prototype (ILD)



Source: stephan Haensel





LPTPC Silicon Envelope Description

OAW



- 2 silicon detector modules build and tested in Vienna:
 - each contains two crossed silicon strip sensors
 - have to fit inside the 35 mm gap • between Magnet and TPC
- moveable support build in Karlsruhe:
 - a sledge on each side of the TPC can position the silicon modules into the beam
- adapted CMS-readout (based on APV25) provided by Karlsruhe (will replaced by the new front-end chip SiTr130-LPNHE)

Institute of High Energy Physics

Source: stephan Haensel

one module (without top cover and light-tight foil)

mounted modules moving along the TPC







LPTPC Silicon Envelope

Preliminary Results

ÓAW





silicon envelope outside the gap between magnet and TPC

• Detector module inside the gap

•Results without TPC-readout



•Combined Data-Taking with one Micromegas Module at the Moment







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Developing larger size silicon tracking prototypes with:

- new sensors
- new front-end electronics
- Combined test beam with calorimetry
- Taking part of a complete slice test beam set-up

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New front-end and readout chip (LPNHE)



2009 – 2010 : Conception-realisation and test of the new version of the SiTr130-128 chip \rightarrow IBM technology, 130nm

- •128 channels + JTAG
- •0.5*1 cm² of silicon, thin down
- •Numerical output with pre-amplifier, shaper, reinitialisation, 8x8 analog pipeline for pulse reconstruction, zero suppression, single ramp ADC, integrated numerical control,
- robustness & flexibility, power cycling, serialization
- Goal: silicon surface optimisation, modular architecture

Under Study : direct connection chip/senseur



SiTr130-128 submitted next year to equip larger silicon tracking prototypes => combined tests with calorimetry



Combined tests with calorimetry



- Providing a reference tracking system with its acquisition system equipped with ASIC SiTr130
- Progress on the design of the elementary module & the connection with FEE chip
- Combined Tests with calorimetry (CALICE, Dual-readout) (mi-2010beginning 2011)
- Flexible configuration (XY, XUV, angle adjustment...)
- Large active area
- Compact integration with low material budget
- Configuration testing: full silicon or hybrid system







- SiLC collaboration have already acquired a large expertise on dedicated and combined test beams
- Developing new silicon prototypes reference and new FEE, related DAQ system and test beam infrastructure
- Next years: work will be pursued with larger prototypes and more combined test beams set-ups
- Pursuing dedicated test beams for R&D on new technologies (sensors and micro-electronics)